

Search Notes

Application/Control No.

10/054,735

Examiner

Huy D. Nguyen

Applicant(s)/Patent under
Reexamination

NAKAMURA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	432.1	7/23/2004	HN
	432.3		
	433		
	435.1		
	435.2		
	435.3		
	436		
	437		
	438		
Updated	search	6/14/2005	HN
Updated	search	10/5/2005	HN
Updated	search	1/27/2006	HN
Updated	search	6/28/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	432.1	6/28/2006	HN
	432.3		
	433		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	7/23/2004	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	6/14/2005	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	10/5/2005	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	1/27/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	6/28/2006	HN
See interference search printout.	6/28/2006	HN